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Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

Details

Product Status	Not For New Designs
Core Processor	ARM® Cortex®-M3
Core Size	32-Bit Single-Core
Speed	80MHz
Connectivity	EBI/EMI, I ² C, IrDA, SmartCard, SPI, UART/USART, USB
Peripherals	Brown-out Detect/Reset, DMA, I ² S, POR, PWM, WDT
Number of I/O	65
Program Memory Size	128KB (128K x 8)
Program Memory Type	FLASH
EEPROM Size	
RAM Size	32K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.6V
Data Converters	A/D 32x12b; D/A 2x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	92-VFLGA Dual Rows, Exposed Pad
Supplier Device Package	92-LGA (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/sim3u157-b-gmr

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

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1. Related Documents and Conventions

1.1. Related Documents

This data sheet accompanies several documents to provide the complete description of the SiM3C1xx device family.

1.1.1. SiM3U1xx/SiM3C1xx Reference Manual

The Silicon Laboratories SiM3U1xx/SiM3C1xx Reference Manual provides detailed functional descriptions for the SiM3C1xx devices.

1.1.2. Hardware Access Layer (HAL) API Description

The Silicon Laboratories Hardware Access Layer (HAL) API provides C-language functions to modify and read each bit in the SiM3C1xx devices. This description can be found in the SiM3xxxx HAL API Reference Manual.

1.1.3. ARM Cortex-M3 Reference Manual

The ARM-specific features like the Nested Vector Interrupt Controller are described in the ARM Cortex-M3 reference documentation. The online reference manual can be found here: http://infocenter.arm.com/help/topic/com.arm.doc.subset.cortexm.m3/index.html#cortexm3.

1.2. Conventions

The block diagrams in this document use the following formatting conventions:

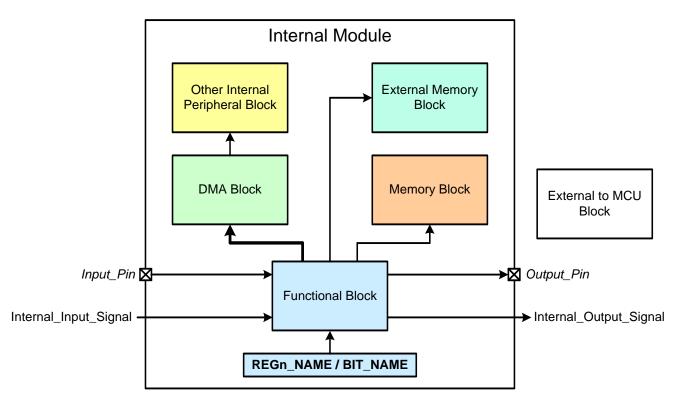


Figure 1.1. Block Diagram Conventions



Table 3.10. SAR ADC (Continued)

Symbol	Test Condition	Min	Тур	Max	Unit						
DNL	12 Bit Mode ²	-1	±0.7	1.8	LSB						
	10 Bit Mode		±0.2	±0.5	LSB						
E _{OFF}	12 Bit Mode, VREF =2.4 V	-2	0	2	LSB						
	10 Bit Mode, VREF =2.4 V	-1	0	1	LSB						
TC _{OFF}			0.004		LSB/°C						
E _M	12 Bit Mode	-0.07	-0.02	0.02	%						
Dynamic Performance with 10 kHz Sine Wave Input 1 dB below full scale, Max throughput											
SNR	12 Bit Mode	62	66	_	dB						
	10 Bit Mode	58	60		dB						
SNDR	12 Bit Mode	62	66	_	dB						
	10 Bit Mode	58	60	_	dB						
THD	12 Bit Mode		78		dB						
	10 Bit Mode		77	_	dB						
SFDR	12 Bit Mode		-79		dB						
	10 Bit Mode		-74		dB						
	DNL E _{OFF} TC _{OFF} E _M Hz Sine Wav SNR SNDR THD	$\begin{tabular}{ c c c c } \hline DNL & 12 & Bit & Mode^2 \\ \hline 10 & Bit & Mode \\ \hline E_{OFF} & 12 & Bit & Mode, & VREF = 2.4 & V \\ \hline 10 & Bit & Mode, & VREF = 2.4 & V \\ \hline TC_{OFF} & & & & & \\ \hline E_M & 12 & Bit & Mode \\ \hline Hz & Sine & Wave & Input 1 & dB & below & full & scale \\ \hline SNR & 12 & Bit & Mode \\ \hline SNR & 12 & Bit & Mode \\ \hline 10 & Bit & Mode \\ \hline SNDR & 12 & Bit & Mode \\ \hline THD & 12 & Bit & Mode \\ \hline THD & 12 & Bit & Mode \\ \hline SFDR & 12 & Bit & Mode \\ \hline \end{tabular}$	$\begin{tabular}{ c c c c } \hline \mathbf{DNL} & $12 \mbox{ Bit Mode}^2$ & -1 \\ \hline $10 \mbox{ Bit Mode}$ & $$ \\ \hline $12 \mbox{ Bit Mode}$, $VREF = $2.4 \ V$ & -2 \\ \hline $10 \mbox{ Bit Mode}$, $VREF = $2.4 \ V$ & -1 \\ \hline $10 \mbox{ Bit Mode}$, $VREF = $2.4 \ V$ & -1 \\ \hline $10 \mbox{ Bit Mode}$, $VREF = $2.4 \ V$ & -1 \\ \hline $10 \mbox{ Bit Mode}$, $VREF = $2.4 \ V$ & -1 \\ \hline $10 \mbox{ Bit Mode}$, $VREF = $2.4 \ V$ & -1 \\ \hline $10 \mbox{ Bit Mode}$, $VREF = $2.4 \ V$ & -1 \\ \hline $10 \mbox{ Bit Mode}$, $VREF = $2.4 \ V$ & -1 \\ \hline $10 \mbox{ Bit Mode}$, $VREF = $2.4 \ V$ & -1 \\ \hline $10 \mbox{ Bit Mode}$, $VREF = $2.4 \ V$ & -1 \\ \hline $10 \mbox{ Bit Mode}$, $VREF = $2.4 \ V$ & -1 \\ \hline -1 \\ \hline $10 \mbox{ Bit Mode}$, -0.07 \\ \hline $12 \mbox{ Bit Mode}$, $12 \mbox{ Bit Mode}$, -1 \\ \hline $10 \mbox{ Bit Mode}$, -1 \\$	$\begin{tabular}{ c c c c c } \hline DNL & 12 & Bit & Mode^2 & -1 & \pm 0.7 \\ \hline 10 & Bit & Mode & & \pm 0.2 \\ \hline 10 & Bit & Mode, & VREF = 2.4 & V & -2 & 0 \\ \hline 10 & Bit & Mode, & VREF = 2.4 & V & -1 & 0 \\ \hline TC_{OFF} & & & 0.004 \\ \hline E_M & 12 & Bit & Mode & -0.07 & -0.02 \\ \hline Hz & Sine & Wave Input 1 & dB & below full & scale, & Max throughput \\ \hline SNR & 12 & Bit & Mode & 62 & 66 \\ \hline 10 & Bit & Mode & 58 & 60 \\ \hline SNDR & 12 & Bit & Mode & 58 & 60 \\ \hline THD & 12 & Bit & Mode & & 78 \\ \hline 10 & Bit & Mode & & 78 \\ \hline 10 & Bit & Mode & & 77 \\ \hline SFDR & 12 & Bit & Mode & & -79 \\ \hline \end{tabular}$	$\begin{tabular}{ c c c c c c } \hline 12 Bit Mode^2 & -1 & \pm 0.7 & 1.8 \\ \hline 10 Bit Mode & & \pm 0.2 & \pm 0.5 \\ \hline 12 Bit Mode, VREF = 2.4 V & -2 & 0 & 2 \\ \hline 10 Bit Mode, VREF = 2.4 V & -1 & 0 & 1 \\ \hline TC_{OFF} & & 0.004 & \\ \hline 10 Bit Mode, VREF = 2.4 V & -1 & 0 & 1 \\ \hline TC_{OFF} & & 0.004 & \\ \hline 10 Bit Mode & -0.07 & -0.02 & 0.02 \\ \hline Hz Sine Wave Input 1 dB below full scale, Max throughput \\ \hline SNR & 12 Bit Mode & 62 & 66 & \\ \hline 10 Bit Mode & 58 & 60 & \\ \hline 10 Bit Mode & 58 & 60 & \\ \hline 10 Bit Mode & 58 & 60 & \\ \hline 10 Bit Mode & 58 & 60 & \\ \hline 10 Bit Mode & 58 & 60 & \\ \hline 10 Bit Mode & -78 & \\ \hline 10 Bit Mode & $ 78 & \\ \hline 10 Bit Mode & $ 77 & \\ \hline $SFDR$ & 12 Bit Mode & $ 77 & \\ \hline $SFDR$ & 12 Bit Mode & $ 77 & \\ \hline \end{tabular}$						

Notes:

1. Absolute input pin voltage is limited by the lower of the supply at VDD and VIO.

2. INL and DNL specifications for 12-bit mode do not include the first or last four ADC codes.

3. The maximum code in 12-bit mode is 0xFFFC. The Slope Error is referenced from the maximum code.



Table 3.15. Temperature Sensor

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Offset	V _{OFF}	T _A = 0 °C	—	760		mV
Offset Error*	E _{OFF}	T _A = 0 °C	—	±14		mV
Slope	М		—	2.8		mV/°C
Slope Error*	EM		—	±120		µV/°C
Linearity			—	1		°C
Turn-on Time				1.8		μs
*Note: Represents one standard deviation	from the mea	an.				•



Table 3.16. Comparator

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Response Time, CMPMD = 00	t _{RESP0}	+100 mV Differential		100	_	ns
(Highest Speed)		-100 mV Differential	_	150	_	ns
Response Time, CMPMD = 11	t _{RESP3}	+100 mV Differential	_	1.4	_	μs
(Lowest Power)		-100 mV Differential		3.5	_	μs
Positive Hysteresis	HYS _{CP+}	CMPHYP = 00	_	0.4	_	mV
Mode 0 (CPMD = 00)		CMPHYP = 01	_	8	_	mV
		CMPHYP = 10		16	_	mV
		CMPHYP = 11	_	33		mV
Negative Hysteresis	HYS _{CP-}	CMPHYN = 00	_	0.4	_	mV
Mode 0 (CPMD = 00)		CMPHYN = 01		-8	_	mV
		CMPHYN = 10	_	-16	_	mV
		CMPHYN = 11	_	-33		mV
Positive Hysteresis	HYS _{CP+}	CMPHYP = 00		0.5	_	mV
Mode 1 (CPMD = 01)		CMPHYP = 01		6	_	mV
		CMPHYP = 10		12	_	mV
		CMPHYP = 11	_	24	_	mV
Negative Hysteresis	HYS _{CP-}	CMPHYN = 00		0.5	_	mV
Mode 1 (CPMD = 01)		CMPHYN = 01		-6.0	_	mV
		CMPHYN = 10	_	-12	_	mV
		CMPHYN = 11		-24	_	mV
Positive Hysteresis	HYS _{CP+}	CMPHYP = 00		0.6	_	mV
Mode 2 (CPMD = 10)		CMPHYP = 01	_	4.5	_	mV
		CMPHYP = 10	_	9.5	_	mV
		CMPHYP = 11		19	_	mV
Negative Hysteresis	HYS _{CP-}	CMPHYN = 00	_	0.6	—	mV
Mode 2 (CPMD = 10)		CMPHYN = 01	_	-4.5	—	mV
		CMPHYN = 10	_	-9.5	—	mV
		CMPHYN = 11		-19	_	mV



Table 3.17. Port I/O

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Standard I/O (PB0, PB1, and PB	32), 5 V Tole	rant I/O (PB3), and RESE	Т			4
Output High Voltage*	V _{OH}	Low Drive, I _{OH} = -2 mA	V _{IO} – 0.7	_	_	V
		High Drive, $I_{OH} = -5 \text{ mA}$	V _{IO} – 0.7	_		V
Output Low Voltage*	V _{OL}	Low Drive, I _{OL} = 3 mA	—	_	0.6	V
		High Drive, I _{OL} = 12.5 mA	—		0.6	V
nput High Voltage	V _{IH}	1.8 <u><</u> V _{IO} <u><</u> 2.0	0.7 x V _{IO}	_	_	V
		2.0 <u><</u> V _{IO} <u><</u> 3.6	V _{IO} – 0.6			V
nput Low Voltage	VIL		—	_	0.6	V
Pin Capacitance	C _{IO}	PB0, PB1 and PB2 Pins	_	4	_	pF
		PB3 Pins	—	7		pF
Weak Pull-Up Current	I _{PU}	V _{IO} = 1.8	-6	-3.5	-2	μA
(Input Voltage = 0 V)		V _{IO} = 3.6	-30	-20	-10	μA
nput Leakage (Pullups off or Analog)	I _{LK}	$0 \le V_{IN} \le V_{IO}$	-1	—	1	μA
nput Leakage Current of Port Bank 3 I/O, V _{IN} above V _{IO}	١L	V _{IO} < V _{IN} < V _{IO} +2.0 V (pins without EXREG functions)	0	5	150	μA
		V _{IO} < V _{IN} < V _{REGIN} (pins with EXREG functions)	0	5	150	μA
High Drive I/O (PB4)			I I			I
Output High Voltage	V _{OH}	Standard Mode, Low Drive, I _{OH} = −3 mA	V _{IOHD} – 0.7	—		V
		Standard Mode, High Drive, I _{OH} = -10 mA	V _{IOHD} – 0.7			V
Output Low Voltage	V _{OL}	Standard Mode, Low Drive, I _{OH} = 3 mA	—	—	0.6	V
		Standard Mode, High Drive, I _{OH} = 12.5 mA	—	—	0.6	V
Output Rise Time	t _R	Slew Rate Mode 0, V _{IOHD} = 5 V	_	50	_	ns
		Slew Rate Mode 1, V _{IOHD} = 5 V	—	300		ns
		Slew Rate Mode 2, V _{IOHD} = 5 V	—	1		μs
		Slew Rate Mode 3, V _{IOHD} = 5 V	—	3	_	μs



Table 3.17. Port I/O (Continued)

Parameter	Symbol	Test Condition	Min	Тур	Мах	Unit
P-Channel Source Current Limit	I _{SRCL}	Mode 0	_	0.8		mA
$(2.7 V \leq VIOHD \leq 6 V,$		Mode 1	_	1.25		
V _{OH} = VIOHD – 0.8 V) See Figure 3.2		Mode 2	_	1.75		
See Figure 5.2		Mode 3	_	2.5		
		Mode 4	_	3.5		
		Mode 5	_	4.75		
		Mode 6	_	7		
		Mode 7	_	9.5		
		Mode 8	_	14		
		Mode 9	_	18.75		
		Mode 10	_	28.25	_	
		Mode 11	_	37.5	_	
		Mode 12	_	56.25		
		Mode 13	_	75	_	
		Mode 14	_	112.5		
		Mode 15	_	150		
Total P-Channel Source Current on P4.0-P4.5 (DC)	I _{SRCLT}		-	—	400	mA
Pin Capacitance	C _{IO}		_	30		pF
Weak Pull-Up Current in Low Volt- age Mode	I _{PU}	V _{IOHD} = 1.8 V	-6	-3.5	-2	μA
		V _{IOHD} = 3.6 V	-30	-20	-10	μA
Weak Pull-Up Current in High Volt- age Mode	I _{PU}	V _{IOHD} = 2.7 V	-15	-10	-5	μA
		V _{IOHD} = 6 V	-30	-20	-10	μA
Input Leakage (Pullups off)	I _{LK}		-1		1	μA
*Note: RESET does not drive to logic h	igh. Specifica	itions for RESET V _{OL} adhe	ere to the low d	rive setting.		



4.1. Power

4.1.1. LDO and Voltage Regulator (VREG0)

The SiM3C1xx devices include two internal regulators: the core LDO Regulator and the Voltage Regulator (VREG0).

The LDO Regulator converts a 1.8–3.6 V supply to the core operating voltage of 1.8 V. This LDO consumes little power and provides flexibility in choosing a power supply for the system.

The Voltage Regulator regulates from 5.5 to 2.7 V and can serve as an input to the LDO. This allows the device to be powered from up to a 5.5 V supply without any external components other than bypass capacitors.

4.1.2. Voltage Supply Monitor (VMON0)

The SiM3C1xx devices include a voltage supply monitor which allows devices to function in known, safe operating condition without the need for external hardware. The supply monitor includes additional circuitry that can monitor the main supply voltage and the VREGIN input voltage divided by 4 (VREGIN / 4).

The supply monitor module includes the following features:

- Main supply "VDD Low" (VDD below the early warning threshold) notification.
- Holds the device in reset if the main VDD supply drops below the VDD Reset threshold.
- VREGIN divided by 4 (VREGIN / 4) supply "VREGIN Low" notification.

4.1.3. External Regulator (EXTVREG0)

The External Regulator provides all the circuitry needed for a high-power regulator except the power transistor (NPN or PNP) and current sensing resistor (if current limiting is enabled).

The External Regulator module has the following features:

- Interfaces with either an NPN or PNP external transistor that serves as the pass device for the high current regulator.
- Automatic current limiting.
- Automatic foldback limiting.
- Sources up to 1 A for use by external circuitry.
- Variable output voltage from 1.8–3.6 V in 100 mV steps.

4.1.4. Power Management Unit (PMU)

The Power Management Unit on the SiM3C1xx manages the power systems of the device. On power-up, the PMU ensures the core voltages are a proper value before core instruction execution begins. It also recognizes and manages the various wake sources for low-power modes of the device.

The PMU module includes the following features:

- Up to 16 pin wake inputs can wake the device from Power Mode 9.
- The Low Power Timer, RTC0 (alarms and oscillator fail), Comparator 0, and the RESET pin can also serve as wake sources for Power Mode 9.
- All PM9 wake sources (except for the RESET pin) can also reset the Low Power Timer or RTC0 modules.
- Disables the level shifters to pins and peripherals to further reduce power usage in PM9. These level shifters must be re-enabed by firmware after exiting PM9.
- Provides a PMU_Asleep signal to a pin as an indicator that the device is in PM9.



4.1.5. Device Power Modes

The SiM3C1xx devices feature four low power modes in addition to normal operating mode. Several peripherals provide wake up sources for these low power modes, including the Low-Power Timer (LPT0), RTC0 (alarms and oscillator failure notification), Comparator 0, and PMU Pin Wake.

In addition, all peripherals can have their clocks disabled to reduce power consumption whenever a peripheral is not being used using the clock control (CLKCTRL) registers.

4.1.5.1. Normal Mode (Power Mode 0)

Normal Mode is the default mode of the device. The core and peripherals are fully operational, and instructions are executed from flash memory.

4.1.5.2. Power Mode 1

In Power Mode 1 the core and peripherals are fully operational, with instructions executing from RAM. Compared with Normal Mode, the active power consumption of the device in PM1 is reduced. Additionally, at higher speeds in PM1, the core throughput can also be increased because RAM does not require additional wait states that reduce the instruction fetch speed.

4.1.5.3. Power Mode 2

In Power Mode 2 the core halts and any enabled peripherals continue to run at the selected clock speed. The power consumption in PM2 corresponds to the AHB and APB clocks left enabled, thus the power can be tuned to the optimal level for the needs of the application. To place the device in PM2, the core should execute a wait-for-interrupt (WFI) or wait-for-event (WFE) instruction. If the WFI instruction is called from an interrupt service routine, the interrupt that wakes the device from PM2 must be of a sufficient priority to be recognized by the core. It is recommended to perform both a DSB (Data Synchronization Barrier) and an ISB (Instruction Syncronization Barrier) operation prior to the WFI to ensure all bus accesses complete. When operating from the LFOSC0 with the DMACTRL0 AHB clock disabled, PM2 can achieve similar power consumption to PM3, but with the ability to wake on APB-clocked interrupts. For example, enabling only the APB clock to the Ports will allow the firmware to wake on a PMATCH0, PBEXT0 or PBEXT1 interrupt with minimal impact on the supply current.

4.1.5.4. Power Mode 3

In Power Mode 3, the AHB and APB clocks are halted. The device may only wake from enabled interrupt sources which do not require the APB clock (RTC0ALRM, RTC0FAIL, LPTIMER0, VDDLOW and VREGLOW). A special fast wake option allows the device to operate at a very low level from the RTC0TCLK or LFOSC0 oscillator while in PM3, but quickly switch to the faster LPOSC0 when the wake event occurs. Because the current consumption of these blocks is minimal, it is recommended to use the fast wake option.

The device will enter PM3 on a WFI or WFE instruction. Because all AHB master clocks are disabled, the LPOSC will automatically halt and go into a low-power suspended state. If the WFI instruction is called from an interrupt service routine, the interrupt that wakes the device from PM3 must be of a sufficient priority to be recognized by the core. It is recommended to perform both a DSB (Data Synchronization Barrier) and an ISB (Instruction Synchronization Barrier) operation prior to the WFI to ensure all bus access is complete.

4.1.5.5. Power Mode 9

In Power Mode 9, the core and all peripherals are halted, all clocks are stopped, and the pins and peripherals are set to a lower power mode. In addition, standard RAM contents are not preserved, though retention RAM contents are still available after exiting the power mode. This mode provides the lowest power consumption for the device, but requires an appropriate reset to exit. The available reset sources to wake from PM9 are controlled by the Power Management Unit (PMU).

Before entering PM9, the desired reset source(s) should be configured in the PMU. The SLEEPDEEP bit in the ARM System Control Register should be set, and the PMSEL bit in the RSTSRC0_CONFIG register must be set to indicate that PM9 is the desired power mode.

The device will enter PM9 on a WFI or WFE instruction, and remain in PM9 until a reset configured by the PMU occurs. It is recommended to perform both a DSB (Data Synchronization Barrier) and an ISB (Instruction Synchronization Barrier) operation prior to the WFI to ensure all bus access is complete.



- Internal transmit and receive FIFOs with flush capability and support for byte, half-word, and word reads and writes.
- Data bit lengths from 5 to 9 bits.
- Programmable inter-packet transmit delays.
- Auto-baud detection with support for the LIN SYNC byte.
- Automatic parity generation (with enable).
- Automatic start and stop generation.
- Transmit and receive hardware flow-control.
- Independent inversion correction for TX, RX, RTS, and CTS signals.
- IrDA modulation and demodulation with programmable pulse widths.
- Smartcard ACK/NACK support.
- Parity error, frame error, overrun, and underrun detection.
- Multi-master and half-duplex support.
- Multiple loop-back modes supported.

4.6.4. SPI (SPI0, SPI1)

SPI is a 3- or 4-wire communication interface that includes a clock, input data, output data, and an optional select signal.

The SPI module includes the following features:

- Supports 3- or 4-wire master or slave modes.
- Supports up to 10 MHz clock in master mode and 5 MHz clock in slave mode.
- Support for all clock phase and slave select (NSS) polarity modes.
- 16-bit programmable clock rate.
- Programmable MSB-first or LSB-first shifting.
- 8-byte FIFO buffers for both transmit and receive data paths to support high speed transfers.
- Programmable FIFO threshold level to request data service for DMA transfers.
- Support for multiple masters on the same data lines.

4.6.5. I2C (I2C0, I2C1)

The I2C interface is a two-wire, bi-directional serial bus. The two clock and data signals operate in open-drain mode with external pull-ups to support automatic bus arbitration.

Reads and writes to the interface are byte oriented with the I2C interface autonomously controlling the serial transfer of the data. Data can be transferred at up to 1/8th of the APB clock as a master or slave, which can be faster than allowed by the I2C specification, depending on the clock source used. A method of extending the clock-low duration is available to accommodate devices with different speed capabilities on the same bus.

The I2C interface may operate as a master and/or slave, and may function on a bus with multiple masters. The I2C provides control of SDA (serial data), SCL (serial clock) generation and synchronization, arbitration logic, and start/ stop control and generation.

The I2C module includes the following features:

- Standard (up to 100 kbps) and Fast (400 kbps) transfer speeds.
- Can operate down to APB clock divided by 32768 or up to APB clock divided by 8.
- Support for master, slave, and multi-master modes.
- Hardware synchronization and arbitration for multi-master mode.
- Clock low extending (clock stretching) to interface with faster masters.
- Hardware support for 7-bit slave and general call address recognition.
- Firmware support for 10-bit slave address decoding.
- Ability to disable all slave states.
- Programmable clock high and low period.
- Programmable data setup/hold times.



4.7. Analog

4.7.1. 12-Bit Analog-to-Digital Converters (SARADC0, SARADC1)

The SARADC0 and SARADC1 modules on SiM3C1xx devices are Successive Approximation Register (SAR) Analog to Digital Converters (ADCs). The key features of the SARADC module are:

- Single-ended 12-bit and 10-bit modes.
- Supports an output update rate of 250 k samples per second in 12-bit mode or 1 M samples per second in 10-bit mode.
- Operation in low power modes at lower conversion speeds.
- Selectable asynchronous hardware conversion trigger with hardware channel select.
- Output data window comparator allows automatic range checking.
- Support for Burst Mode, which produces one set of accumulated data per conversion-start trigger with programmable power-on settling and tracking time.
- Conversion complete, multiple conversion complete, and FIFO overflow and underflow flags and interrupts supported.
- Flexible output data formatting.
- Sequencer allows up to 8 sources to be automatically scanned using one of four channel characteristic profiles without software intervention.
- Eight-word conversion data FIFO for DMA operations.
- Multiple SARADC modules can work together synchronously or by interleaving samples.
- Includes two internal references (1.65 V fast-settling, 1.2/2.4 V precision), support for an external reference, and support for an external signal ground.

4.7.2. Sample Sync Generator (SSG0)

The SSG module includes a phase counter and a pulse generator. The phase counter is a 4-bit free-running counter clocked from the SARADC module clock. Counting-up from zero, the phase counter marks sixteen equally-spaced events for any number of SARADC modules. The ADCs can use this phase counter to start a conversion. The programmable pulse generator creates a 50% duty cycle pulse with a period of 16 phase counter ticks. Up to four programmable outputs available to external devices can be driven by the pulse generator with programmable polarity and a defined output setting when the pulse generator is stopped.

The Sample Sync Generator module has the following features:

- Connects multiple modules together to perform synchronized actions.
- Outputs a clock synchronized to the internal sampling clock used by any number of SARADC modules to pins for use by external devices.
- Includes a phase counter, pulse generator, and up to four programmable outputs.

4.7.3. 10-Bit Digital-to-Analog Converter (IDAC0, IDAC1)

The IDAC takes a digital value as an input and outputs a proportional constant current on a pin. The IDAC module includes the following features:

- 10-bit current DAC with support for four timer, up to seven external I/O, on demand, and SSG0 output update triggers.
- Ability to update on rising, falling, or both edges for any of the external I/O trigger sources (DACnTx).
- Supports an output update rate greater than 600 k samples per second.
- Support for three full-scale output modes: 0.5 mA, 1.0 mA and 2.0 mA.
- Four-word FIFO to aid with high-speed waveform generation or DMA interactions.
- Individual FIFO overrun, underrun, and went-empty interrupt status sources.
- Support for multiple data packing formats, including: single 10-bit sample per word, dual 10-bit samples per word, or four 8-bit samples per word.
- Support for left- and right-justified data.



6. Pin Definitions and Packaging Information

6.1. SiM3C1x7 Pin Definitions

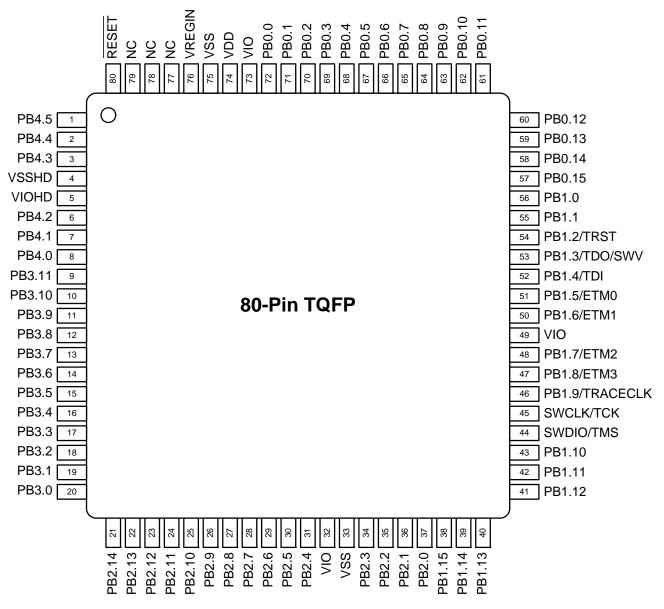


Figure 6.1. SiM3C1x7-GQ Pinout



SiM3C1xx

Pin Name	Туре	Pin Numbers TQFP-80	Pin Numbers LGA-92	Crossbar Capability (see Port Config Section)	Port Match	External Memory Interface (m = muxed mode)	Port-Mapped Level Shifter	Output Toggle Logic	External Trigger Inputs	Analog or Additional Functions
VSS	Ground	33 75	B15 B34							
VDD	Power (Core)	74	A44							
VIO	Power (I/O)	32 49 73	A19 A29 A43							
VREGIN	Power (Regulator)	76	A45							
VSSHD	Ground (High Drive)	4	B2							
VIOHD	Power (High Drive)	5	A3							
RESET	Active-low Reset	80	A48							
SWCLK/TCK	Serial Wire/JTAG	45	B20							
SWDIO/TMS	Serial Wire/JTAG	44	A27							
PB0.0	Standard I/O	72	B33	XBR0	\checkmark					ADC0.0
PB0.1	Standard I/O	71	B32	XBR0	V					ADC0.1 CS0.0
PB0.2	Standard I/O	70	A42	XBR0	~					ADC0.2 CS0.1
PB0.3	Standard I/O	69	B31	XBR0	~					ADC0.3 CS0.2
PB0.4	Standard I/O	68	A41	XBR0	~					ADC0.4 CS0.3
PB0.5	Standard I/O	67	B30	XBR0	~					ADC0.5 CS0.4
PB0.6	Standard I/O	66	A40	XBR0	\checkmark					CS0.5
PB0.7	Standard I/O	65	B29	XBR0	~					ADC0.6 CS0.6 IVC0.0

Table 6.1. Pin Definitions and alternate functions for SiM3C1x7



Table 6.1. Pin Definitions and alternate	e functions for SiM3C1x7	(Continued)
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Din Nama	Toma	Pin Numbers TQFP-80	Pin Numbers LGA-92	Crossbar Capability (see Port Config Section)	Port Match	External Memory Interface (m = muxed mode)	Port-Mapped Level Shifter	Output Toggle Logic	External Trigger Inputs	Analog or Additional Functions
Pin Name PB1.9/ TRACECLK	Type Standard I/O /ETM	ä 46	ā A28	ن ق XBR0	<u>√</u>	ά£	Рс	õ	<u>ش</u>	ਪ ਛੋ ADC1.9
PB1.10	Standard I/O	43	A26	XBR0	~	A23m/ A15			DMA0T1	ADC1.8
PB1.11	Standard I/O	42	A25	XBR0	~	A22m/ A14			DMA0T0	ADC1.7
PB1.12	Standard I/O	41	D3	XBR0	~	A21m/ A13				ADC1.6
PB1.13	Standard I/O	40	A24	XBR0	~	A20m/ A12			ADC0T15 WAKE.0	ADC1.5 CS0.10
PB1.14	Standard I/O	39	A23	XBR0	~	A19m/ A11			ADC1T15 WAKE.1	ADC1.4 CS0.11
PB1.15	Standard I/O	38	A22	XBR0	~	A18m/ A10			WAKE.2	ADC1.3 CS0.12
PB2.0	Standard I/O	37	B17	XBR1	V	A17m/ A9	LSI0	Yes	INT0.0 INT1.0 WAKE.3	ADC1.2 CS0.13
PB2.1	Standard I/O	36	A21	XBR1	~	A16m/ A8	LSI1	Yes	INT0.1 INT1.1 WAKE.4	ADC1.1 CS0.14
PB2.2	Standard I/O	35	B16	XBR1	~	AD15m/ A7	LSI2	Yes	INT0.2 INT1.2 WAKE.5	ADC1.0 CS0.15 PMU_Asleep
PB2.3	Standard I/O	34	A20	XBR1	~	AD14m/ A6	LSI3	Yes	INT0.3 INT1.3 WAKE.6	
PB2.4	Standard I/O	31	B14	XBR1	~	AD13m/ A5	LSI4	Yes	INT0.4 INT1.4 WAKE.7	
PB2.5	Standard I/O	30	A18	XBR1	\checkmark	AD12m / A4	LSI5	Yes	INT0.5 INT1.5	



Pin Name	Туре	Pin Numbers TQFP-80	Pin Numbers LGA-92	Crossbar Capability (see Port Config Section)	Port Match	External Memory Interface (m = muxed mode)	Port-Mapped Level Shifter	Output Toggle Logic	External Trigger Inputs	Analog or Additional Functions
PB3.4	5 V Tolerant I/O	16	A9	XBR1	\checkmark	ŌĒ			INT0.9 INT1.9 WAKE.8	CMP0P.4 CMP1P.4
PB3.5	5 V Tolerant I/O	15	B7	XBR1	~	ALEm			DAC0T2 DAC1T2 INT0.10 INT1.10 WAKE.9	CMP0N.4 CMP1N.4
PB3.6	5 V Tolerant I/O	14	A8	XBR1	~	CS0			DAC0T3 DAC1T3 INT0.11 INT1.11 WAKE.10	CMP0P.5 CMP1P.5
PB3.7	5 V Tolerant I/O	13	B6	XBR1	~	BE1			DAC0T4 DAC1T4 LPT0T1 INT0.12 INT1.12 WAKE.11	CMP0N.5 CMP1N.5
PB3.8	5 V Tolerant I/O	12	A7	XBR1	~	CS1			DAC0T5 DAC1T5 LPT0T2 INT0.13 INT1.13 WAKE.12	CMP0P.6 CMP1P.6 EXREGSP
PB3.9	5 V Tolerant I/O	11	B5	XBR1	\checkmark	BE0			DAC0T6 DAC1T6 INT0.14 INT1.14 WAKE.13	CMP0N.6 CMP1N.6 EXREGSN
PB3.10	5 V Tolerant I/O	10	B4	XBR1	\checkmark				INT0.15 INT1.15 WAKE.14	CMP0P.7 CMP1P.7 EXREGOUT
PB3.11	5 V Tolerant I/O	9	B3	XBR1	\checkmark				WAKE.15	CMP0N.7 CMP1N.7 EXREGBD

Table 6.1. Pin Definitions and alternate functions for SiM3C1x7 (Continued)



Pin Name	Туре	Pin Numbers	Crossbar Capability (see Port Config Section)	Port Match	External Memory Interface (m = muxed mode)	Port-Mapped Level Shifter	Output Toggle Logic	External Trigger Inputs	Analog or Additional Functions
PB1.8	Standard I/O	30	XBR0	~	AD14m/ A6			WAKE.2	ADC1.3 CS0.12
PB1.9	Standard I/O	29	XBR0	\checkmark	AD13m/ A5			WAKE.3	ADC1.2 CS0.13
PB1.10	Standard I/O	28	XBR0	\checkmark	AD12m/ A4			DMA0T1 WAKE.4	ADC1.1 CS0.14
PB1.11	Standard I/O	27	XBR0	~	AD11m/ A3			DMA0T0 WAKE.5	ADC1.0 CS0.15 PMU_Asleep
PB1.12	Standard I/O	26	XBR0	~	AD10m/ A2			WAKE.6	
PB1.13	Standard I/O	23	XBR0	~	AD9m/ A1				
PB1.14	Standard I/O	22	XBR0	~	AD8m/ A0				
PB1.15	Standard I/O	21	XBR0	\checkmark	AD7m/ D7				
PB2.0	Standard I/O	20	XBR1	$\mathbf{\mathbf{Y}}$	AD6m/ D6	LSI0	Yes	INT0.0 INT1.0	
PB2.1	Standard I/O	19	XBR1	\checkmark	AD5m/ D5	LSI1	Yes	INT0.1 INT1.1	
PB2.2	Standard I/O	18	XBR1	>	AD4m/ D4	LSI2	Yes	INT0.2 INT1.2	CMP0N.0 CMP1N.0 RTC0TCLK_OUT
PB2.3	Standard I/O	17	XBR1	\checkmark	AD3m/ D3	LSI3	Yes	INT0.3 INT1.3	CMP0P.0 CMP1P.0
PB3.0	5 V Tolerant I/O	16	XBR1	\checkmark	AD2m/ D2				CMP0P.1 CMP1P.1
PB3.1	5 V Tolerant I/O	15	XBR1	~	AD1m/ D1				CMP0N.1 CMP1N.1





		1					
Pin Name	Туре	Pin Numbers	Crossbar Capability (see Port Config Section)	Port Match	Output Toggle Logic	External Trigger Inputs	Analog or Additional Functions
PB0.8	Standard I/O	26	XBR0	\checkmark			ADC0.14 ADC1.14
PB0.9	Standard I/O	25	XBR0	~			ADC0.15 ADC1.15
PB0.10	Standard I/O	22	XBR0	\checkmark		DMA0T1	ADC1.8
PB0.11	Standard I/O	21	XBR0	\checkmark		DMA0T0	ADC1.7
PB0.12	Standard I/O	20	XBR0	~		ADC0T15 WAKE.0	ADC1.5 CS0.10
PB0.13	Standard I/O	19	XBR0	\checkmark		ADC1T15 WAKE.1	ADC1.4 CS0.11
PB0.14	Standard I/O	18	XBR0	~		WAKE.2	ADC1.3 CS0.12
PB0.15	Standard I/O	17	XBR0	~		WAKE.3	ADC1.2 CS0.13
PB1.0	Standard I/O	16	XBR0	~		WAKE.4	ADC1.1 CS0.14
PB1.1	Standard I/O	15	XBR0	\checkmark		WAKE.5	ADC1.0 CS0.15 PMU_Asleep
PB1.2	Standard I/O	12	XBR0	~			CMP0N.0 CMP1N.0 RTC0TCLK_OUT
PB1.3	Standard I/O	11	XBR0	\checkmark			CMP0P.0 CMP1P.0
PB3.0	5 V Tolerant I/O	10	XBR1	~		DAC0T0 DAC1T0 LPT0T0 INT0.0 INT1.0 WAKE.12	CMP0P.1 CMP1P.1 EXREGSP

Table 6.3. Pin Definitions and Alternate Functions for SiM3C1x4 (Continued)



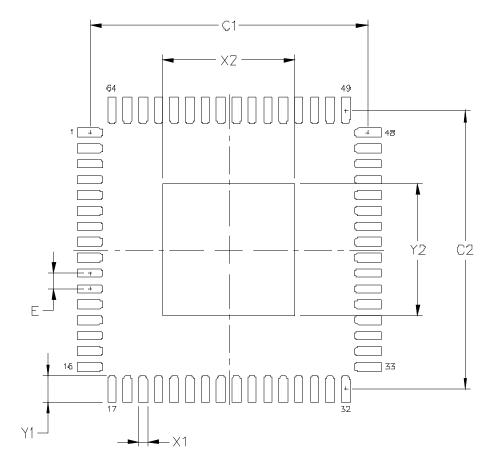


Figure 6.11. QFN-64 Landing Diagram

Dimension	mm
C1	8.90
C2	8.90
E	0.50
X1	0.30
Y1	0.85
X2	4.25
Y2	4.25
Notes:	

Table 6.9. QFN-64 Landing Diagram Dimensions

- 1. All dimensions shown are in millimeters (mm).
- 2. This Land Pattern Design is based on the IPC-7351 guidelines.
- 3. All dimensions shown are at Maximum Material Condition (MMC). Least Material Condition (LMC) is calculated based on a Fabrication Allowance of 0.05 mm.



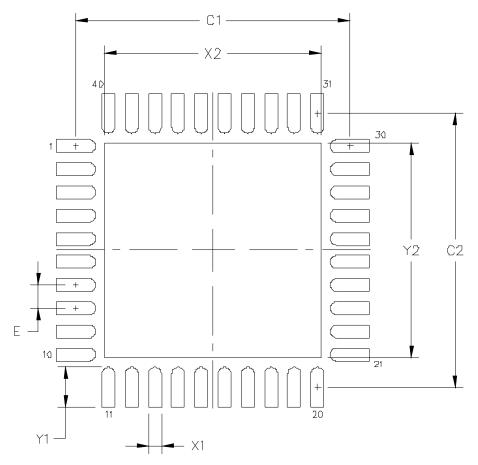


Figure 6.15. QFN-40 Landing Diagram

Dimension	mm		
C1	5.90		
C2	5.90		
E	0.50		
X1	0.30		
Y1	0.85		
X2	4.65		
Y2	4.65		
Notos			

Table 6.13. QFN-40 Landing Diagram Dimensions

Notes:

- 1. All dimensions shown are in millimeters (mm).
- 2. This Land Pattern Design is based on the IPC-7351 guidelines.
- **3.** All dimensions shown are at Maximum Material Condition (MMC). Least Material Condition (LMC) is calculated based on a
 - Fabrication Allowance of 0.05 mm.



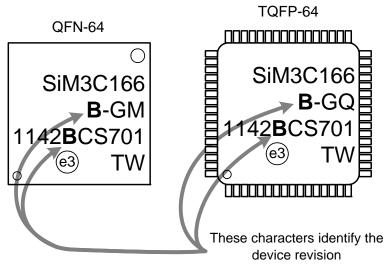
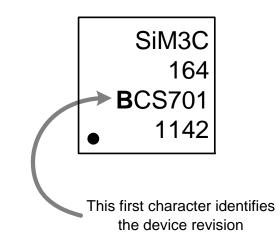


Figure 7.3. SiM3C1x6 Revision Information





7.2. Comparator Rising/Falling Edge Flags in Debug Mode (CMP0, CMP1)

7.2.1. Problem

On Revision A and Revision B devices, if the comparator output is high, the comparator rising and falling edge flags will both be set to 1 upon single-step or exit from debug mode.

7.2.2. Impacts

Firmware using the rising and falling edge flags to make decisions may see a false trigger of the comparator if the output of the comparator is high during a debug session. This does not impact the non-debug operation of the device.

7.2.3. Workaround

There is not a system-agnostic workaround for this issue.

7.2.4. Resolution

This issue exists on Revision A and Revision B devices. It may be corrected in a future device revision.

